



NSAI
Standards

Irish Standard
I.S. EN 60749-44:2016

Semiconductor devices - Mechanical and climatic test methods - Part 44: Neutron beam irradiated single event effect (SEE) test method for semiconductor devices

I.S. EN 60749-44:2016

Incorporating amendments/corrigenda/National Annexes issued since publication:

The National Standards Authority of Ireland (NSAI) produces the following categories of formal documents:

I.S. xxx: Irish Standard — national specification based on the consensus of an expert panel and subject to public consultation.

S.R. xxx: Standard Recommendation — recommendation based on the consensus of an expert panel and subject to public consultation.

SWiFT xxx: A rapidly developed recommendatory document based on the consensus of the participants of an NSAI workshop.

This document replaces/revises/consolidates the NSAI adoption of the document(s) indicated on the CEN/CENELEC cover/Foreword and the following National document(s):

NOTE: The date of any NSAI previous adoption may not match the date of its original CEN/CENELEC document.

This document is based on:

EN 60749-44:2016

Published:

2016-10-21

*This document was published
under the authority of the NSAI
and comes into effect on:*

2016-11-08

ICS number:

NOTE: If blank see CEN/CENELEC cover page

NSAI
1 Swift Square,
Northwood, Santry
Dublin 9

T +353 1 807 3800
F +353 1 807 3838
E standards@nsai.ie
W NSAI.ie

Sales:
T +353 1 857 6730
F +353 1 857 6729
W standards.ie

Údarás um Chaighdeáin Náisiúnta na hÉireann

National Foreword

I.S. EN 60749-44:2016 is the adopted Irish version of the European Document EN 60749-44:2016, Semiconductor devices - Mechanical and climatic test methods - Part 44: Neutron beam irradiated single event effect (SEE) test method for semiconductor devices

This document does not purport to include all the necessary provisions of a contract. Users are responsible for its correct application.

Compliance with this document does not of itself confer immunity from legal obligations.

In line with international standards practice the decimal point is shown as a comma (,) throughout this document.

This page is intentionally left blank

EUROPEAN STANDARD

EN 60749-44

NORME EUROPÉENNE

EUROPÄISCHE NORM

October 2016

ICS 31.080.01

English Version

**Semiconductor devices - Mechanical and climatic test methods -
Part 44: Neutron beam irradiated single event effect (SEE) test
method for semiconductor devices
(IEC 60749-44:2016)**

Dispositifs à semiconducteurs - Méthodes d'essais
mécaniques et climatiques - Partie 44: Méthode d'essai des
effets d'un événement isolé (SEE) irradié par un faisceau
de neutrons pour des dispositifs à semiconducteurs
(IEC 60749-44:2016)

Halbleiterbauelemente - Mechanische und klimatische
Prüfverfahren - Teil 44: Prüfverfahren zur Einzelereignis-
Effekt-Neutronenbestrahlung von Halbleiterbauelementen
(IEC 60749-44:2016)

This European Standard was approved by CENELEC on 2016-08-25. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this European Standard the status of a national standard without any alteration.

Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the CEN-CENELEC Management Centre or to any CENELEC member.

This European Standard exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the CEN-CENELEC Management Centre has the same status as the official versions.

CENELEC members are the national electrotechnical committees of Austria, Belgium, Bulgaria, Croatia, Cyprus, the Czech Republic, Denmark, Estonia, Finland, Former Yugoslav Republic of Macedonia, France, Germany, Greece, Hungary, Iceland, Ireland, Italy, Latvia, Lithuania, Luxembourg, Malta, the Netherlands, Norway, Poland, Portugal, Romania, Slovakia, Slovenia, Spain, Sweden, Switzerland, Turkey and the United Kingdom.



European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

CEN-CENELEC Management Centre: Avenue Marnix 17, B-1000 Brussels

EN 60749-44:2016

European foreword

The text of document 47/2303/FDIS, future edition 1 of IEC 60749-44, prepared by IEC/TC 47 "Semiconductor devices" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN 60749-44:2016.

The following dates are fixed:

- latest date by which the document has to be (dop) 2017-05-25
implemented at national level by
publication of an identical national
standard or by endorsement
- latest date by which the national (dow) 2019-08-25
standards conflicting with the
document have to be withdrawn

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. CENELEC [and/or CEN] shall not be held responsible for identifying any or all such patent rights.

Endorsement notice

The text of the International Standard EC 60749-44:2016 was approved by CENELEC as a European Standard without any modification.

In the official version, for Bibliography, the following note has to be added for the standard indicated :

IEC 60749-38 NOTE Harmonized as EN 60749-38.

This is a free preview. Purchase the entire publication at the link below:

[Product Page](#)

-
- Looking for additional Standards? Visit Intertek Inform Infostore
 - Learn about LexConnect, All Jurisdictions, Standards referenced in Australian legislation
-